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# **Electromagnetic Interference and Compatibility, Volume II**

Guest Editor:

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Deadline for manuscript submissions:

closed (28 February 2022)

## **Message from the Guest Editor**

In this Special Issue, contributions addressing electromagnetic compatibility and interference topics in the broadest sense, including but not limited to IC- and system-level immunity and susceptibility issues of either information and communication technology (ICT) and power electronic systems, either in emerging IoT, smart grid, electric vehicles applications or in more traditional systems, EMC-oriented simulation and measurement techniques, and EMC applications of ML and AI, are welcome and encouraged.

- EMC in IoT applications
- Power electronics EMC
- IC-level FMC.
- System level EMC
- Electromagnetic interference
- Electromagnetic compatibility
- FMC simulations
- EMC measurements
- EMI mitigation techniques
- EMC applications of Artificial Intelligence/machine learning











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### **Editor-in-Chief**

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### **Message from the Editor-in-Chief**

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